
P1696

Submitter Email: john.jendzurski@nist.gov
Type of Project: Revision to IEEE Standard 1696-2013
Project Request Type: Initiation / Revision
PAR Request Date: 21 Oct 2020
PAR Approval Date: 10 Feb 2021
PAR Expiration Date: 31 Dec 2025
PAR Status: Active
Root Project: 1696-2013

1.1 Project Number: P1696
1.2 Type of Document: Standard
1.3 Life Cycle: Full Use

2.1 Project Title: Standard for Terminology and Test Methods for Circuit Probes
Change to Title: ~~IEEE~~ Standard for Terminology and Test Methods for Circuit Probes

3.1 Working Group: Subcommittee on Probe Standards(IM/WM&A/Probe)

3.1.1 Contact Information for Working Group Chair:

Name: John Jendzurski

Email Address: john.jendzurski@nist.gov

3.1.2 Contact Information for Working Group Vice Chair:

None

3.2 Society and Committee: IEEE Instrumentation and Measurement Society/TC10 - Waveform Generation Measurement and Analysis(IM/WM&A)

3.2.1 Contact Information for Standards Committee Chair:

Name: N Paulter

Email Address: nicholas.paulter@nist.gov

3.2.2 Contact Information for Standards Committee Vice Chair:

Name: William Boyer

Email Address: db1505@comcast.net

3.2.3 Contact Information for Standards Representative:

None

4.1 Type of Ballot: Individual

4.2 Expected Date of submission of draft to the IEEE SA for Initial Standards Committee Ballot:
Oct 2022

4.3 Projected Completion Date for Submittal to RevCom: Apr 2023

5.1 Approximate number of people expected to be actively involved in the development of this project: 20

5.2 Scope of proposed standard: This standard provides test method(s) and describes transfer (artifact) standards for characterizing electrical circuit probes and probes systems. The systems may include waveform acquisition hardware and software and signal/waveform analysis software. The probe includes the mechanism by which the circuit is contacted. This method and standard applies to all individual probes having one signal conductor and one ground conductor or two signal conductors, and having an input impedance greater than the impedance of the circuit under test.

5.3 Is the completion of this standard contingent upon the completion of another standard? No

5.4 Purpose: This document will not include a purpose clause.

5.5 Need for the Project: There is a market need based on the plethora of probe products used by industry for circuit characterization, design verification and debugging. This document will benefit probe manufacturers by providing them with a means of comparing their products to those from another manufacturer and, consequently, a basis from which to improve their products. The probe user will benefit from continued improvements in probes, from knowing how to characterize and select probes properly, and in understanding how the probe affects measured waveforms.

5.6 Stakeholders for the Standard: The stakeholders for this standard are the aerospace industry the computing industry, data communications industry, telecommunications industry, and test and measurement instrument manufacturers

6.1 Intellectual Property

6.1.1 Is the Standards Committee aware of any copyright permissions needed for this project?

No

6.1.2 Is the Standards Committee aware of possible registration activity related to this project?

No

7.1 Are there other standards or projects with a similar scope? No

7.2 Is it the intent to develop this document jointly with another organization? No

8.1 Additional Explanatory Notes: The need for the P1696 revision is to keep the standard active.